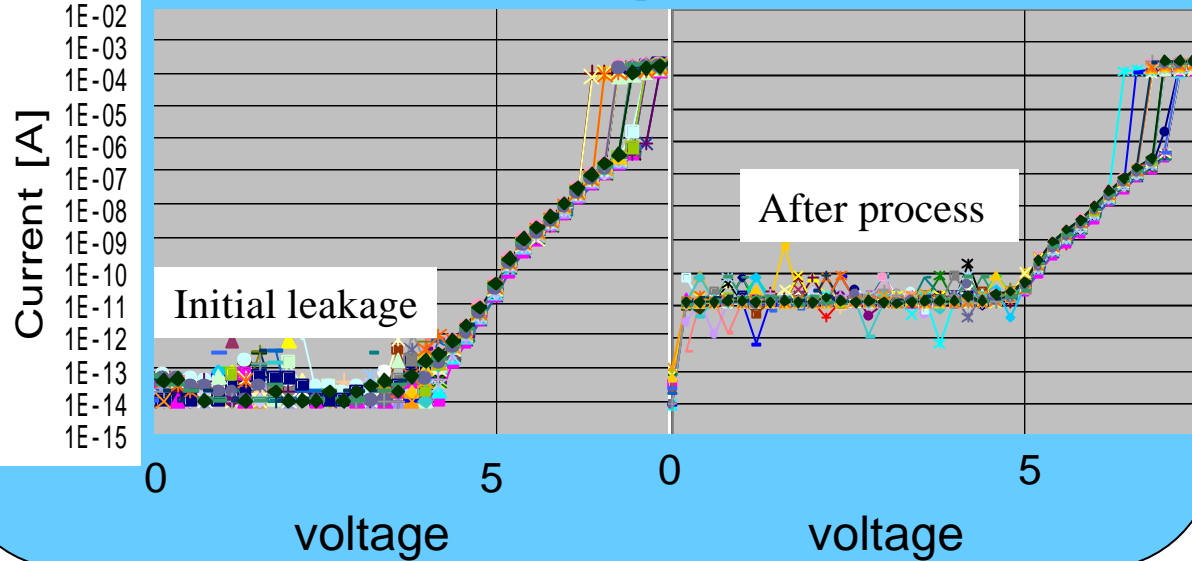


Damage evaluation by increase in leakage current prior to break
As a Philtech new product:PD3003



Damage Region of
Oxide Break Down
Caused for
Charge-stress induced
E'-defect increase

Damage evaluation service by oxide break down as a simple product

